Readout electronics for LumiCal detector

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Front-end electronics development

2 Development of 10 bit pipeline ADC

Peripheral circuits (DAC, Bandgap, LVDS)



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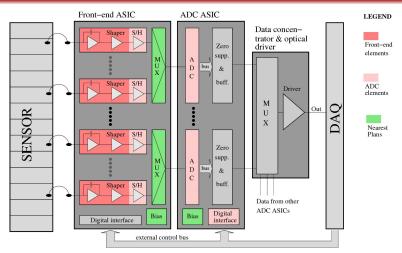
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Front-End

ADC 00000000 Peripheral circuits (DAC, Bandgap, LVDS)

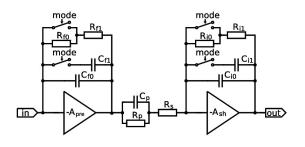
Summary

LumiCal Readout System



Present developments done in 0.35 μm CMOS technology, not necessarily final choice...

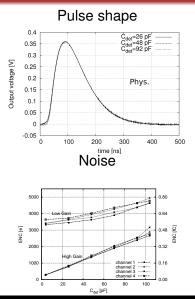
Front-end requirements (old)

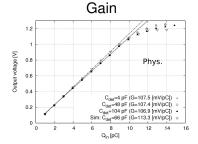


Components

- Charge amplifier
- Pole zero cancellation
- 1st order shaper
- $C_{det} = 10 \div 100 \text{ pF} \rightarrow \text{charge sensitive amplifier}$
- $\Delta t_{bunch} \simeq 300 \ {
 m ns}
 ightarrow {
 m T_{peak}} \simeq 60 \ {
 m ns}$
- Two independent modes: physics and calibration (MIP)
 - \rightarrow switched gain in preamplifier and shaper
- Physics mode: $Q_{max} \approx 10 \text{ pC} \rightarrow C_f \approx 10 \text{ pF}$
- Calibration mode: S/N > 10 for MIP requested

Front-end measurements





- Prototype 8 channels ASIC produced
- 4 channels with resistive (R_f) and 4 with MOS feedback in preamplifier
- Both versions fully functional
- Front-end linear up to about 10 pC, works with C_{det} up to about 1000 pF

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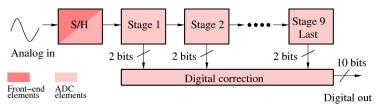
ront-Er ⊙●	าd	ADC 00000000	Peripheral circu	its (DAC, Bandgap,	LVDS)	Sumn	hary				
Front-end parameters summary											
-	Mode	Gain [mV/fC]	Noise@50pF [fC]	Linearity [pC]	Rate [MHz]	Crosstalk [%]					
-	Physics Calibration	0.107 ≈20	0.62 0.28	10 0.035	3 3	≈1 ≈0.1					

- Similar results for both R_F and MOS configurations (MOS slightly better)
- Crosstalk needs to be measured with sensor fanout
- Power consumption per channel is 8.9 mW
- Noise in details:
 - Noise_{phys}[el] = $3300 + 13 \cdot C_{in}[pF]$
 - Noise_{cal}[el] = $170 + 26 \cdot C_{in}[pF]$

M. Idzik, Sz. Kulis, D. Przyborowski, "Development of front-end electronics for the luminoisty detector at ILC" Nucl. Instr. and Meth. A 608 (2009) pp. 169-174,

ADC Requirements and archirecture

- 10 bit resolution
- Sampling frequency 3-30 MHz (depending on number of FE channels per ADC)
- With and without S/H (S/H can be a part of front-end)
- Power efficient, power and clock ON/OFF
- Fully differential pipeline architecture



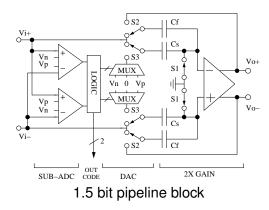
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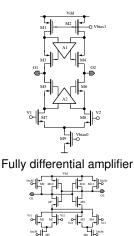
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Peripheral circuits (DAC, Bandgap, LVDS)

Summary

Pipeline ADC - Design



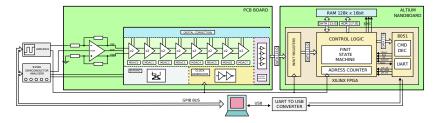


Dynamic latch comparator

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ADC Test	Setun	



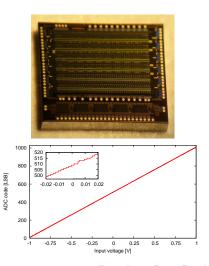
- Signal from AWG2021 generator
- External single-ended to differential converter
- FPGA based (Altium nanoboard with Xilinx Spartan2E) DAQ

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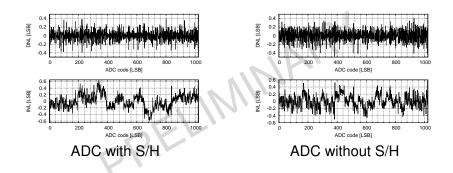
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ADC - prototypes and measurements

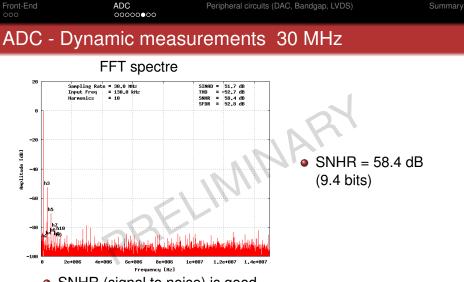
- 1st prototype: only 8 pipeline stages
- 2nd prototype: 9 stages + S/H + digital correction + clock and power switching
- No reference voltages yet applied externally
- Both prototypes fully functional
- Both prototypes work up to about 30 MHz



ADC - Linearity



Both ADC versions show good differential (DNL<0.5 LSB) and integral linearity (INL<1 LSB)



- SNHR (signal to noise) is good
- To measure harmonic distortions the setup needs to be improved (in progress)...

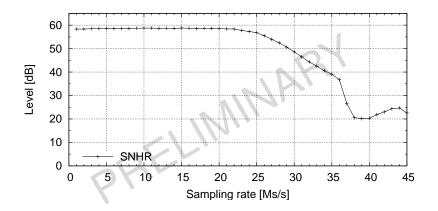
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Peripheral circuits (DAC, Bandgap, LVDS)

Summary

ADC - Dynamic measurements

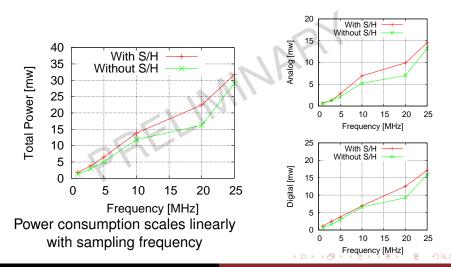


- Good SNHR up to about 25 MHz
- The scan versus input signal frequency f_{in} also needs to be done...

Peripheral circuits (DAC, Bandgap, LVDS)

Summary

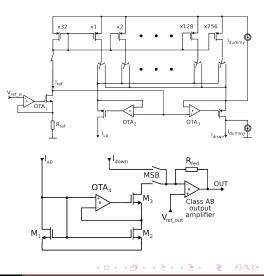
ADC - Power scaling



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Design of low power 10 bit general purpose DAC

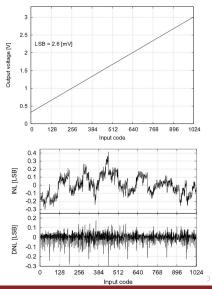
- Current steering architecture
- High-swing voltage output
- Power cons. < 0.6 mW</p>
- Core area 0.18 mm²



Peripheral circuits (DAC, Bandgap, LVDS)

DAC measurements

- DAC fully functional
- Power cons. below 0.6 mW
- max INL < 0.42 LSB</p>
- max DNL < 0.42 LSB</p>
- Efective number of bits ENOB=9.85
- Update rate up to few hundred kHz



Other peripherals

- Bandgap reference voltage and temperature sensor circuit designed, fabricated and just bonded, to be tested...
- Fast (>500 MHz) LVDS transmitter and receiver designed, fabricated and just bonded, to be tested...

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Summary - present status

- Front-end ASICs designed, fabricated and matching the specifications
- Front-end 8 channels prototypes ready for tests with sensors, fanout and hopefully for test beam
- New 10-bit piepline ADC prototypes fully functional and preliminary results confirm expectations
- More ADC tests needed (power switching, harmonics, power scaling)
- Very low power 10 bit DAC designed, fabricated and matching the specifications, ready to be used
- Bandgap reference designed and fabricated, to be tested
- Fast LVDS pads designed and fabricated, to be tested

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Summary - future plans

- Proceed with tests (ADC, LVDS, bandgap), in progress...
- Tests of the readout chain comprising of sensor, fanout and front-end, in progress...
- Prepare the setup for test beam (as soon as the readout chain will be tested)
- Design and submission of complete multichannel (>=8) ADC, in progress, submission soon...

Digital processing & data concentrator

- Waiting for better detector specification \rightarrow data flux
- Pure digital design so can be done fast in comparison to front-end and ADC
- Will first be designed and tested with FPGA
- After FPGA tests ASIC implementation should be fast (mounth or two)

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Test setup (beam) preparation

- Silicon sensors from Hammamatsu ready and preliminary I-V and C-V measurements performed
- First fanout structures designed and fabricated
- Prototype front-end (8 channels) ASICs will be used
- External ADC will be used since the prototype ADC ASIC is not yet multichannel
- PCB board for test setup designed and produced

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